

PCN-PLP-002105

# **Product Change Notice**

Issue Date: December 09, 2020

#### **Change Type:**

Add ASE-KH as a 2<sup>nd</sup> source wafer sort (i.e. wafer probe) site

#### Parts Affected:

BCM89230B1BCFBG

BCM89230B1BCFBGT

BCM89231B1BPBG

BCM89231B1BPBGT

BCM89241B1BFBG

BCM89241B1BFBGT

BCM89251B1BFBG

BCM89251B1BFBGT

BCM89530B1BPBG

BCM89530B1BPBGT

BCM89531B1BPBG

DCIVIOSSSIBIBI DG

BCM89531B1BPBGT

BCM89535B1BPBG

BCM89535B1BPBGT

BCM89541B1BFBG

BCM89541B1BFBGT

BCM89550B1BFBG

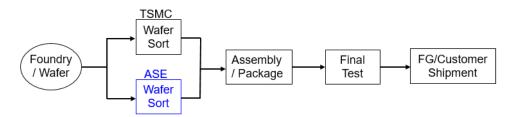
BCM89550B1BFBGT

BCM89551B1BFBG

BCM89551B1BFBGT

### **Description and Extent of Change:**

Electrical wafer sort testing is currently performed on this product at TSMC Fab 14 (Tainan, Taiwan R.O.C.). Broadcom will add ASE-KH (Kaohsiung City, Taiwan R.O.C.) as a 2<sup>nd</sup> source for wafer sort. There is no change to Foundry, Assembly or Final Test – see updated flow below.



Note that ASE-KH is a Broadcom qualified automotive wafer sort supplier.

## **Reasons for Change:**

Increase wafer sort capacity and flexibility

# Effect of Change on Fit, Form, Function, Quality, or Reliability:

The device specification, test limits, SYA/SBL limits, and D-PAT will remain the same, which will ensure product electrical performance remains the same. Appropriate correlation has been performed to ensure <u>no impact</u> on Fit, Form, Function, Quality, or Reliability. In addition, the devices are fully tested at Hot and Cold temperature at Final Test.



# **Effective Date of Change:**

Product shipments using this change will begin after 1-Feb-2021. Timing of shipment of parts tested at ASE-KH will vary by part number depending on customer demand and inventory levels.

# **Correlation Information:**

The TSMC-to-ASE correlation activity has successfully completed. See the table below for details.

Note: All of the part numbers listed in this PCN use the same chip design and wafer sort test program.

Correlation Item	ASE-KH Result	OK/NOK
Tester	Same as at TSMC	OK
Test DIB and probe card	Same as at TSMC	OK
Test Program	Same as at TSMC	OK
Test time / # of tests	Same as at TSMC	OK
SYA/SBL limits	Same as at TSMC	OK
D-PAT limits	Same as at TSMC	OK
Loop 50 times; 5 units/site (2 sites) @ Room Temp	500/500 pass	OK
Run 1 correlation wafer (yield/reject comparison)	Pass	OK
Analog test parameter correlation	Pass	OK

Please contact your Broadcom field sales engineer or Contact Center for any questions or support requirements. Please return any response as soon as possible, but not to exceed 30 days.